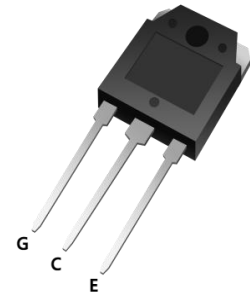
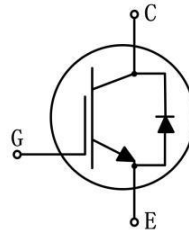


Trench Field-stop IGBT Discrete

Parameter	Value	Unit
V_{CE}	650	V
I_C	40	A
$V_{CE(sat)}$	1.9	V



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Features

- Trench and field-stop technology
- Low saturation voltage: $V_{CE(sat),typ}=1.9V$
@ $I_C=40A$ and $T_C=100^\circ C$
- Low switching loss: $E_{off,typ}=0.95mJ$
@ $I_C=40A$ and $T_C=100^\circ C$
- Easy parallel switching capability

Applications

- Energy storage
- Solar string inverter
- Uninterruptible Power Supply

Maximum Ratings

Parameter	Symbol	Value	Unit
Collector-Emitter Voltage	V_{CES}	650	V
Gate-Emitter Voltage	V_{GES}	± 20	V
Continuous collector current($T_C=25^\circ C$)	I_C	80	A
Continuous collector current($T_C=100^\circ C$)		40	A
Pulse collector current, $t_p=1ms$	I_{CM}	160	A
Diode continuous forward current($T_C=100^\circ C$)	I_F	40	A
Diode maximum current, t_p limited by T_{vjmax}	I_{FM}	160	A
Power dissipation($T_C=25^\circ C$)	P_{tot}	300	W
Maximum junction temperature	T_{vj}	-40 to+175	$^\circ C$
Maximum storage temperature	T_{STG}	-55 to+150	$^\circ C$

Thermal Characteristics

Parameter	Symbol	Value			Unit
		Min.	Typ.	Max.	
Thermal resistance,junction to case for IGBT	$R_{th(j-c)}$	-	-	0.5	$^\circ C/W$
Thermal resistance,junction to case for Diode	$R_{th(j-c)}$	-	-	1.1	$^\circ C/W$
Thermal resistance,junction to ambient	$R_{th(j-a)}$	-	-	40	$^\circ C/W$

Electrical Characteristics of IGBT ($T_{vj}=25^{\circ}\text{C}$ unless otherwise specified)

Parameter	Symbol	Test Condition	Value			Unit
			Min.	Typ.	Max.	
Collector-emitter breakdown voltage	$V_{(BR)CES}$	$V_{GE}=0V, I_C=250\mu A$	650	-	-	V
Collector-emitter leakage current	I_{CES}	$V_{CE}=650V, V_{GE}=0V$	-	-	10	μA
Gate leakage current, forward	I_{GES}	$V_{GE}=\pm 20V, V_{CE}=0V$	-	-	100	nA
Gate-emitter threshold voltage	$V_{GE(th)}$	$V_{GE}=V_{CE}, I_C=1mA$	4.0	5.0	6.0	V
Collector-emitter saturation voltage	$V_{CE(sat)}$	$V_{GE}=15V, I_C=40A$	-	1.9	-	V
		$V_{GE}=15V, I_C=40A, T_{vj}=150^{\circ}\text{C}$	-	2.3	-	V
Input capacitance	C_{ies}	$V_{CE}=30V$	-	2480	-	pF
Output capacitance	C_{oes}	$V_{GE}=0V$	-	95	-	pF
Reverse transfer capacitance	C_{res}	$f=1MHz$	-	21	-	pF
Gate charge	Q_G	$V_{CC}=520V$ $V_{GE}=15V$ $I_C=40A$	-	78	-	nC
Turn-on delay time	$t_{d(on)}$	$V_{CC}=400V$ $V_{GE}=15V$ $I_C=40A$ $R_G=10\Omega$ Inductive load	-	32	-	ns
Rise time	t_r		-	55	-	ns
Turn-off delay time	$t_{d(off)}$		-	106	-	ns
Fall time	t_f		-	51	-	ns
Turn-on energy	E_{on}		-	0.9	-	mJ
Turn-off energy	E_{off}		-	0.5	-	mJ
Turn-on delay time	$t_{d(on)}$		-	28	-	ns
Rise time	t_r		-	52	-	ns
Turn-off delay time	$t_{d(off)}$		-	128	-	ns
Fall time	t_f		-	75	-	ns
Turn-on energy	E_{on}	$T_{vj}=150^{\circ}\text{C}$	-	0.9	-	mJ
Turn-off energy	E_{off}		-	0.9	-	mJ

Diode Characteristics

Parameter	Symbol	Test Condition	Value			Unit
			Min.	Typ.	Max.	
Diode forward voltage	V_F	$I_F=40A$	-	2.4	-	V
		$I_F=40A, T_{vj}=150^{\circ}\text{C}$	-	1.8	-	V
Diode reverse recovery time	t_{rr}	$V_R=400V$	-	68	-	ns
Diode peak reverse recovery current	I_{rrm}	$I_F=40A$	-	15	-	A
Diode reverse recovery charge	Q_{rr}	$diF/dt=-950A/\mu s$	-	522	-	nC
Diode reverse recovery time	t_{rr}	$V_R=400V$	-	106	-	ns
Diode peak reverse recovery current	I_{rrm}	$I_F=40A$	-	24	-	A
Diode reverse recovery charge	Q_{rr}	$T_{vj}=150^{\circ}\text{C}$	-	1423	-	nC

Typical Characteristics

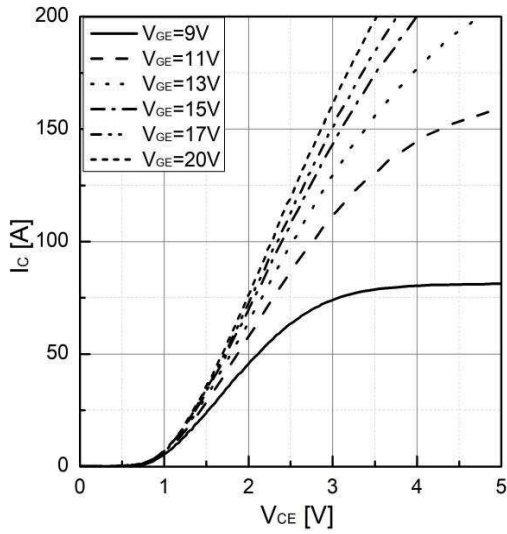


Fig 1. Typical output characteristics ($T_{vj}=25^\circ\text{C}$)

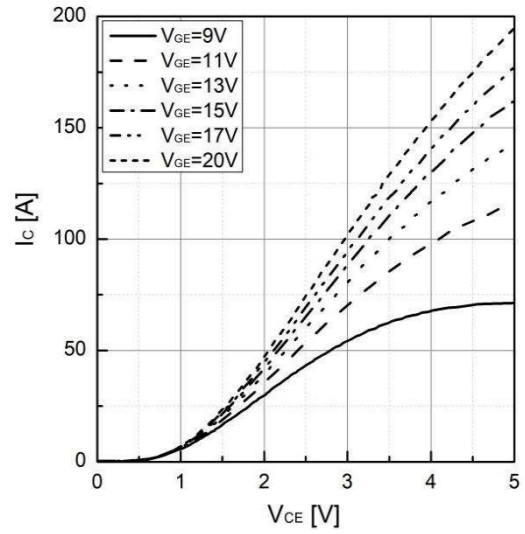


Fig 2. Typical output characteristics ($T_{vj}=150^\circ\text{C}$)

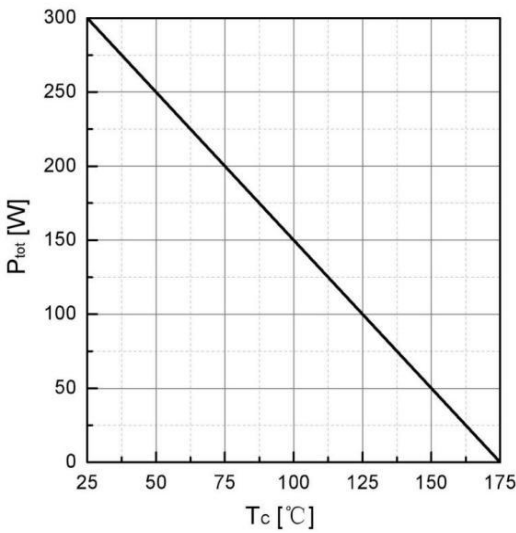


Fig 3. Power dissipation as a function of T_c

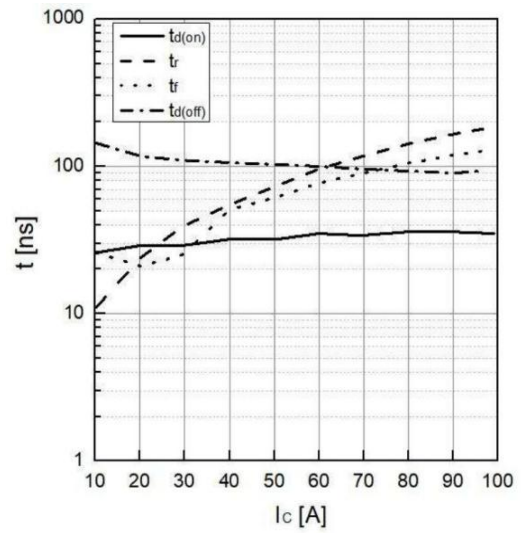


Fig 4. Typical switching time as a function of I_c

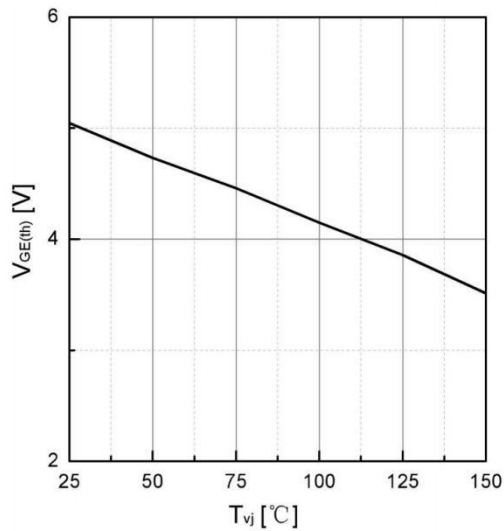


Fig 5. Typical $V_{GE(th)}$ as a function of T_{vj}

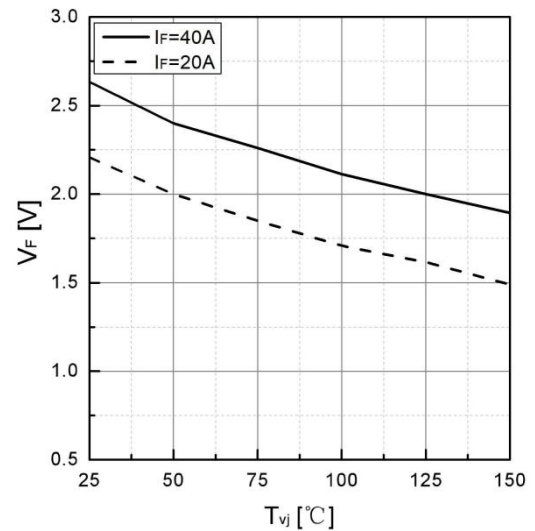


Fig 6. Typical V_F as a function of T_{vj}

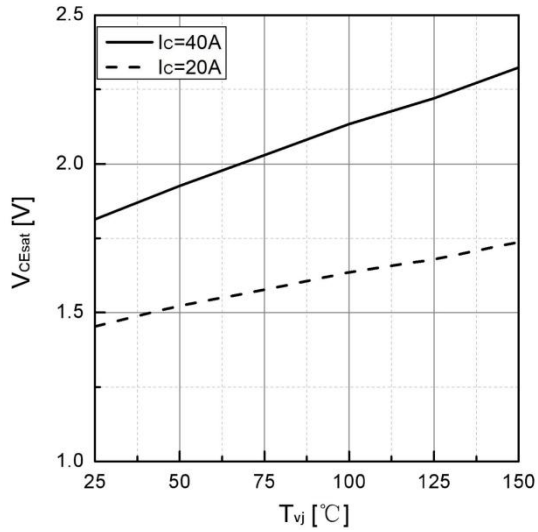


Fig 7. Typical V_{CEsat} as a function of T_{vj}

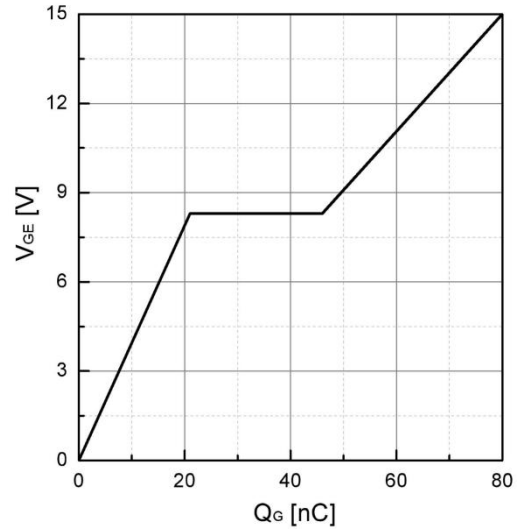


Fig 8. Typical Gate charge

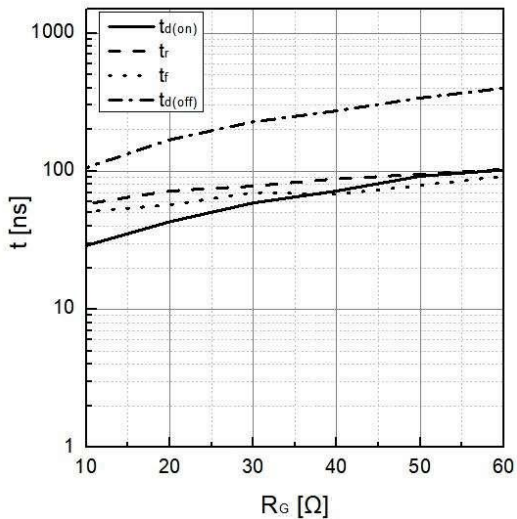


Fig 9. Typical switching times as a function of R_G

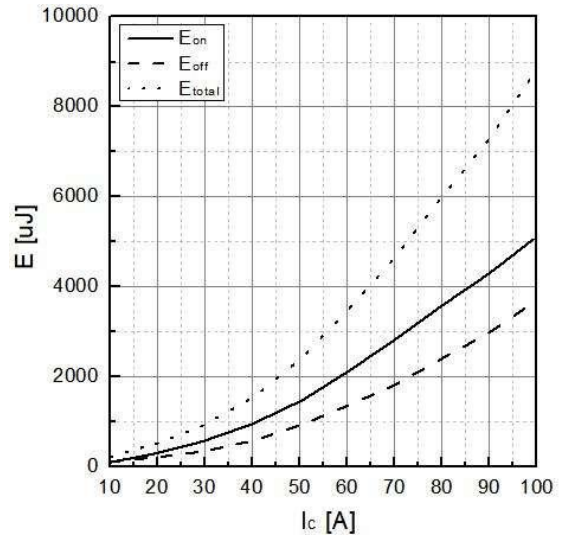


Fig 10. Typical switching energy losses as a function of I_c

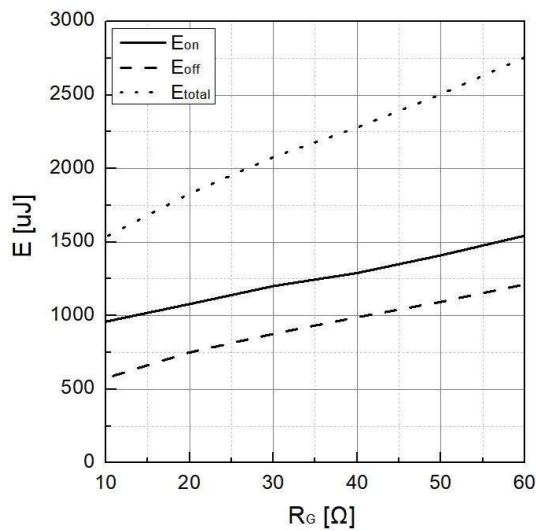


Fig 11. Typical switching energy losses as a function of R_G

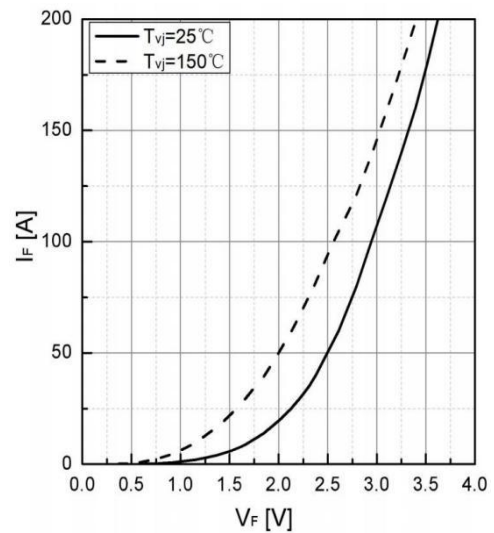


Fig 12. Typical I_F as a function of V_F

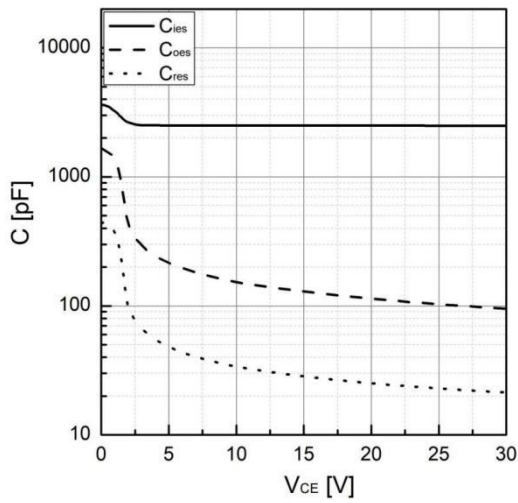


Fig 13. Typical capacitance as a function of V_{CE}
($f=1\text{MHz}, V_{GE}=0\text{V}$)

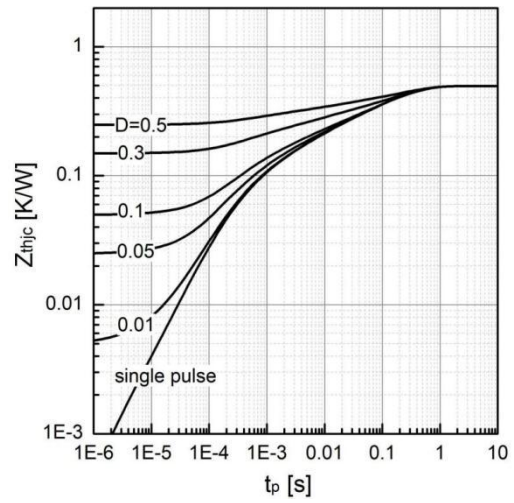
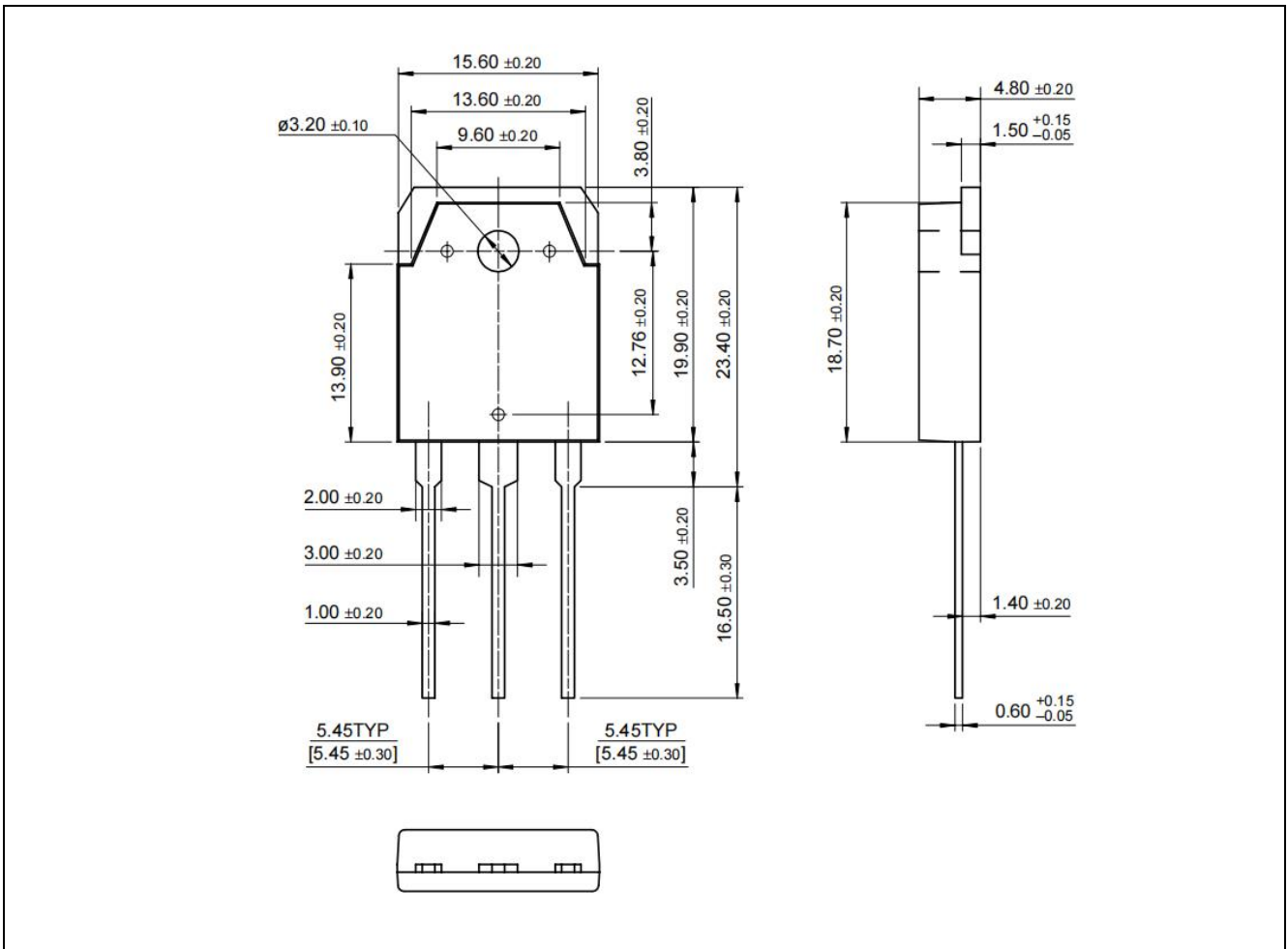


Fig 14. Transient thermal impedance of IGBT

Package Outlines (Unit: mm)

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